

**Search Notes**

Application/Control No.

10/711,115

Examiner

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Applicant(s)/Patent under  
Reexamination

PURCELL ET AL.

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
708	253, 256	6/17/2005	MAI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search Double Patenting Check Data Bases Search (see attached copy)	6/17/2005	MAI